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Supplementary Materials for

Skin-like low-noise elastomeric organic photodiodes

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Fig. S1.

Analysis of mechanical properties of freestanding films. (A) Comparison of experimental and fitted stress curve of e-BHJ. (B) Elasticity vs. strain plot derived from the engineering stress-strain curve.



Fig. S2.

Analysis of photodetector metrics for OPD with e-BHJ on a rigid substrate. (A) Optical power dependence of transient current and photocurrent. (B) Optical power dependence of signal-to-noise ratio.



Fig. S3.

Analysis of photodetector metrics for unstrained e-OPD. (A) Optical power dependence of transient current and photocurrent. (B) Optical power dependence of signal-to-noise ratio.



Fig. S4.

Improved stretchability of e-OPD using 60% pre-strained PDMS/PEDOT:PSS. (A) Structure of pre-strained PDMS/PEDOT:PSS electrode. **(B)** Normalized resistance vs. strain plot

(bottom). (C) Dark current (top) and root-mean-squared noise box plot (bottom).





Comparison of experimental and fitted dark current density using an equivalent circuit model for OPD with e-BHJ on a rigid substrate. (A) Experimental and fitted dark current density. (B) Equivalent circuit (top), corresponding equation (bottom), and physical parameters listed in Table S2.

Table S1.

Freestanding films	Strain at break (%)	Elasticity at 0% (MPa)	Elasticity at 50% (MPa)	Elasticity at 100% (MPa)	Elasticity at 150% (MPa)
r-BHJ	6	259	-	-	-
e-BHJ	189	2.4	0.7	0.3	1.3
SEBS	192	0.8	0.3	0.2	0.5

Elasticity at different strains of freestanding films extracted from the engineering stressstrain plots.

Table S2.

Physical parameters of OPD with e-BHJ on a rigid substrate derived from an equivalent circuit model.

Reverse saturation current density, J_{θ} (pA cm ⁻²)	Ideality factor, <i>n</i>	Series resistance, <i>Rs</i> (Ω)	Shunt resistance, R_P (Ω)
2.5	1.89	5×10 ³	5×10 ¹¹